10:30 Coffee Break

Session SS Special Session Space and Aeronautic systems
Room Cassiopée

chairpersons M. LABRUNEE P. PONS

10:50 SS-1 #17 Stress factors in aircraft electronics: superimpositions, case studies and failure precautions
P. Jacob, G. Nicoletti
Empa Swiss Fed Labs for Materials Testing and Research

11:10 SS-2 #25 A closed-loop voltage prognosis for lithium-ion batteries under dynamic loads using an improved equivalent circuit model
J. Yang1, J. Yu1, D. Tang1, J. Dai2
1Beihang University, 2China Academy of Launch Vehicle Technology R&D Center

11:30 SS-3 #84 Combined Ionizing Radiation & Electromagnetic Interference Test Procedure to Achieve Reliable Integrated Circuits
F. Vargas1, R. Goertl1, P. Villa2, N. Medina3, N. Added3, M. Da Silva4
1Catholic University - PUCRS, 2Federal Institute of Rio Grande do Sul - IFRS, 3University of São Paulo, 4Centro Universitário FEI

11:50 SS-4 #127 Robustness and Reliability Review of Si and SiC FET devices for More-Electric-Aircraft Applications
J. Ortiz Gonzalez, R. Wu, S. N. Agbo, O. Alatise
The University of Warwick

12:10 SS-5 #219 Reliability evaluation of a 0.25µm SiGe technology for space applications
C. Robin, S. Rochette
Thales Alenia Space

12:30 SS-6 #241 Radiation-induced Single Event Transient effects during the Reconfiguration Process of SRAM-based FPGAs
L. Sterpone, C. De Sio, L. Bozzoli, S. Azimi, B. Du
Politecnico di Torino

12:50 Lunch

Session I1-I2 ESD and EMC
Room Cassiopée

chairpersons D. POGANY T. DUBOIS

14:00 Invited paper
EMC & ESD from the technology to the system (Challenge, Trends, application cases)
P. Besse
NXP Semiconductors

14:40 I1-I2-1 #37 Effect of TLP rise time on ESD failure modes of collector-base junction of SiGe heterojunction bipolar transistors
C. Fleury1, D. Pogany2, W. Simbürger3
1CTR Carinthian Tech Research AG, 2Vienna University of Technology, 3Infineon

15:00 I1-I2-2 #39 Topology and design investigation on thin film silicon BIMOS device for ESD protection in FD-SOI technology
P. Galy1, L. De Conti2, M. Vinet3, S. Cristoloveanu4,